

# Formula sheet

$$① J_{\text{drift}} = \sigma E ; J = I/A$$

$$② J_{\text{drift}} = J_{n,\text{drift}} + J_{p,\text{drift}} = (\sigma_n + \sigma_p) E$$

$$③ d\phi = q \rho A v_{ap} dt \Rightarrow I_p = q \rho A v_{ap} \Rightarrow J_p = q \rho v_{ap} = \sigma_p E \Rightarrow \sigma_p = q \rho \frac{v_{ap}}{E} = q \rho \mu_p$$

$$④ \mu = v_{ap}/E \quad \{ \text{mobility} = \text{drift vel. per unit field} \}$$

$$⑤ \mu_p = v_{ap}/E \quad | \quad \alpha_m = -v_{ap}/E \quad | \quad \sigma_m = q n \mu_m \quad | \quad \sigma_p = q \rho \mu_p$$

$$⑥ n \text{ type} \quad p \text{ type} \quad J_{\text{drift}} = q (\alpha_m n + \mu_p p) E = \sigma E \Rightarrow \sigma = q n \mu_m + q \rho \mu_p$$

	n type	p type
maj. carrier	$e^-$	$p^+ / h^+$
mob. maj.	$\approx 1330 \text{ cm}^2/\text{Vs}$	$495 \text{ cm}^2/\text{Vs}$
min. carrier	$p^+ / h^+$	$e^-$
mob. min.	$495 \text{ cm}^2/\text{Vs}$	$\approx 1330 \text{ cm}^2/\text{Vs}$

⑦  $e^-$  & hole mob. reduce monotonically with impurities

$$⑧ \mu = q \epsilon / m^*$$

$$⑨ V_d = q \epsilon E / m^*$$

$$⑩ \frac{1}{\mu_{\text{eff}}} = \frac{1}{\mu_i} + \frac{1}{\mu_p}$$

$$⑪ \frac{1}{\mu_{\text{eff}}} = \frac{1}{\mu_i} + \frac{1}{\mu_p}$$

$$⑫ \mu_p \propto T^{3/2}$$

$$⑬ \mu_i \propto T^{3/2}$$

$$⑭ \mu = \frac{\mu_0}{1 + \epsilon/E_c} \rightarrow \text{low field mobility}$$

\* Electric field  $E$

$$\boxed{\mu = \frac{V_{\text{drift}}}{\text{Elec. field}}}$$

For minority carriers the drift current can be neglected compared with diffusion current in the quasi-neutral regions.

$$J_{n(p)} = q D_n \frac{dn_p}{dx}$$

$$J_{p(n)} = -q D_p \frac{dp_n}{dx}$$

where  $D_n$  and  $D_p$  are the minority carrier diffusion coefficients.

Hence

The electron diffusion current density is equal to the flux density multiplied by the charge of the electron:

$$J_{n(\text{diff})} = -q F_n = q D_n \frac{dn(x)}{dx} \quad (3.40)$$

Similarly for holes,

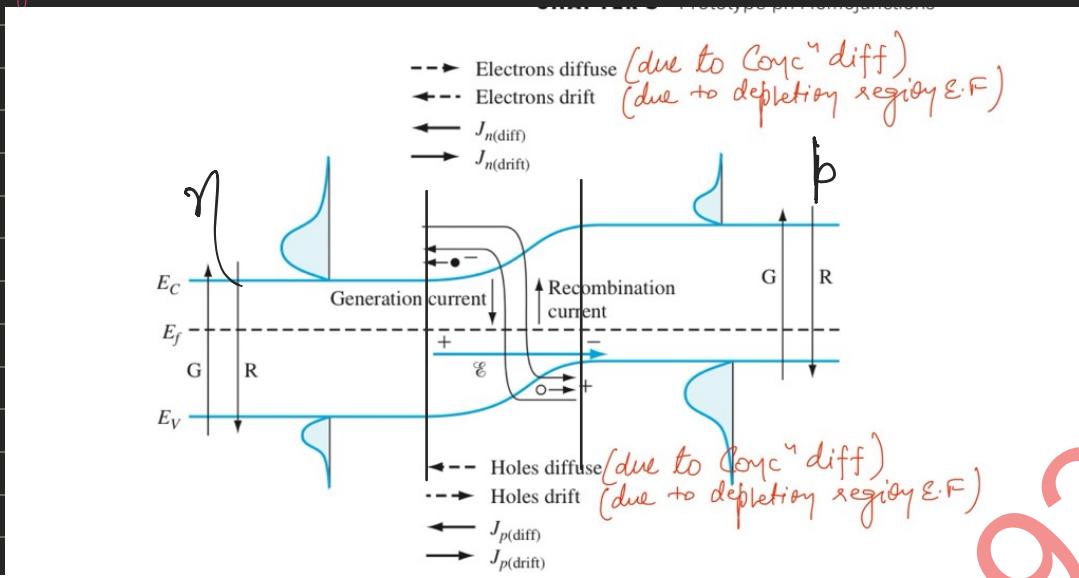
$$J_{p(\text{diff})} = +q F_p = -q D_p \frac{dp(x)}{dx} \quad (3.41)$$

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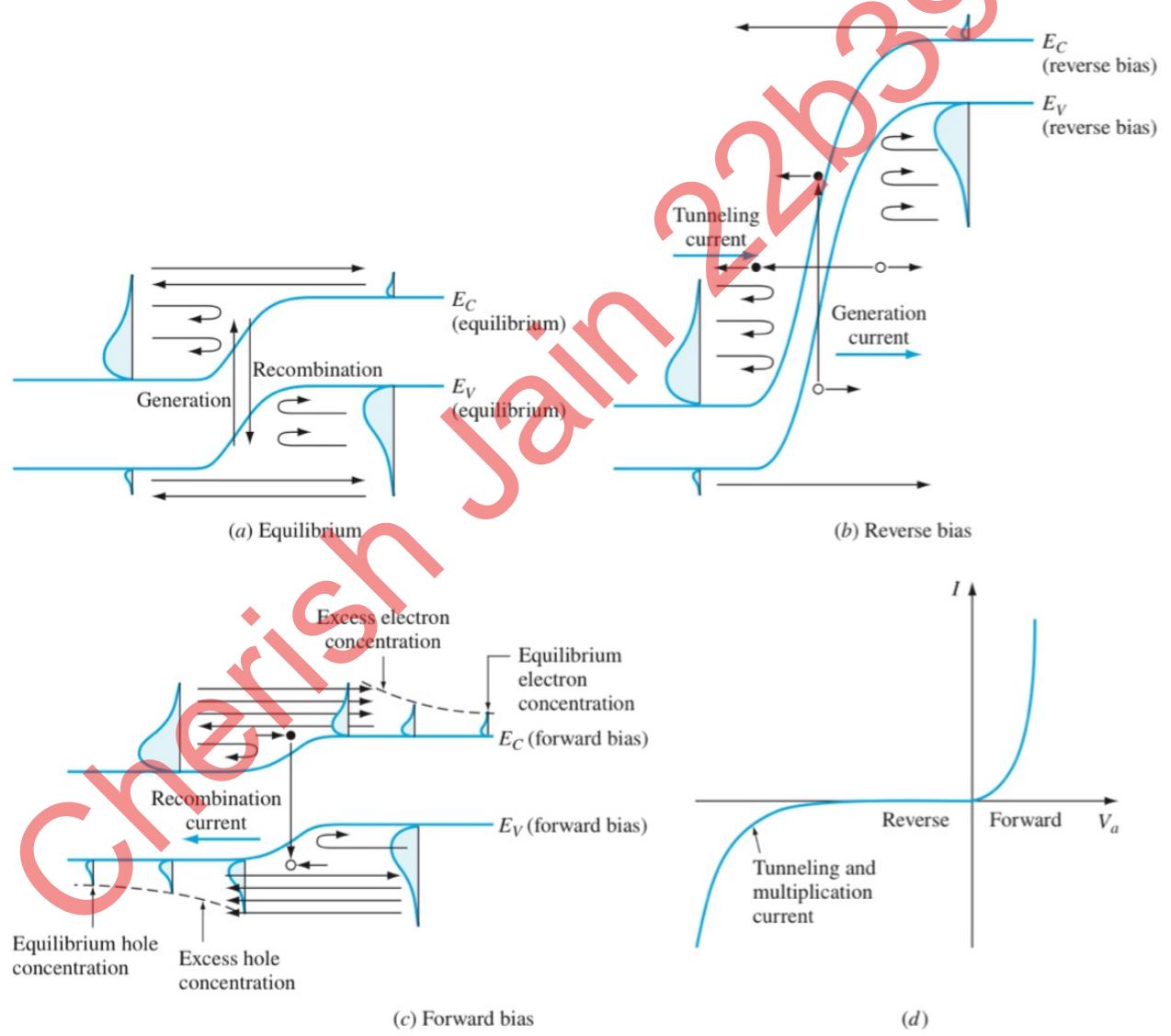
## EXTRA A.

① with ↑ doping ; impurity Band from bottom of Conduction Band to Normally forbidden Band ↑ with inc. in doping

(2)

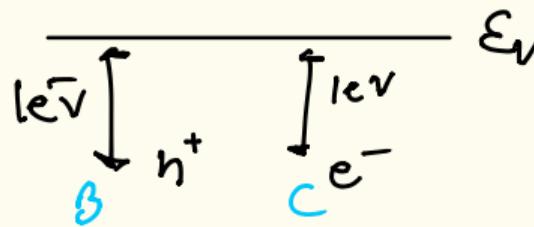
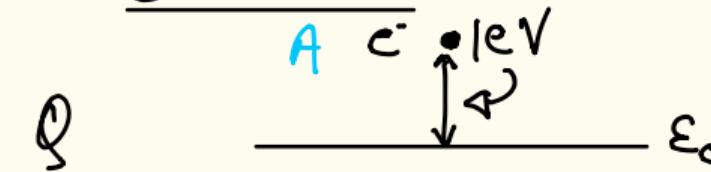


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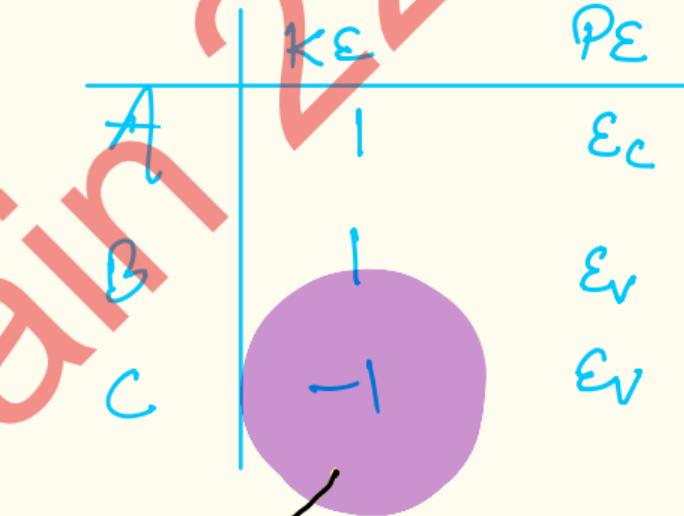
(4)

4 QUIZ - 1



find PE & KE of A, B, C

Sol':



Very  
Imp

# Non-Eq<sup>m</sup> (Bias Applied)

$$F(x_2) - F(x_1) = - \sigma \left( \frac{n \Delta n}{\partial t} \right) \quad \begin{matrix} \text{J} = qF \\ \nabla \end{matrix}$$

$$\frac{J(x_2) - J(x_1)}{\Delta x} = q \left\{ \frac{\partial n}{\partial t} \right\}$$

$$\therefore \frac{\partial J}{\partial x} = q \frac{\partial n}{\partial t} = - \frac{\partial}{\partial t} (-qn) \quad \text{zlo}$$

$$\Rightarrow \frac{\partial J}{\partial x} = - \frac{\partial}{\partial t} (P) \quad \begin{matrix} \nabla \cdot J = - \frac{\partial P}{\partial t} \\ \text{Divergence of } J \end{matrix}$$

$$\text{Now } J_g = qn \mu_n E + q D_n \frac{\partial n}{\partial x}$$

$$\text{also; } \frac{\partial J}{\partial x} = q \frac{\partial n}{\partial t} \quad \therefore$$

$$\text{So; } qn \left[ n \frac{\partial E}{\partial x} + E \frac{\partial n}{\partial x} \right] + q D_n \frac{\partial^2 n}{\partial x^2} = q \frac{\partial n}{\partial t}$$

$$\text{Hence; } \mu_n \left( n \frac{\partial E}{\partial x} + E \frac{\partial n}{\partial x} \right) + D_n \frac{\partial^2 n}{\partial x^2} = \frac{\partial n}{\partial t}$$

$F \rightarrow \text{flux}$

$$\text{if } E=0, \quad D_n \cdot \frac{\partial^2 n}{\partial x^2} = \frac{\partial n}{\partial t} \quad \left\{ \text{Fick's 2nd law} \right\}$$

Drift neglected  $\downarrow$

Excess Carrier Dynamics  $\downarrow$

$D_g \cdot \frac{\partial^2 (\Delta n(x))}{\partial x^2} = \frac{\partial \Delta n}{\partial t}$

But  $n = n_0 + \Delta n$

if min & max @ S.C. I used for upgrad LED

$$\begin{aligned} @ \text{Eq}^m \quad n(x) &= \text{Const.} = n_0 & \text{may be const if S.C. is illuminated uniformly} \\ @ \text{excitation} \quad n(x) &= n_0 + \Delta n(x) & \text{may be non-uniform} \\ & \downarrow & \\ & \text{giving min to S.C.} & \\ & n_0 = f(t) & \end{aligned}$$

$\text{p-type [exp]}$   $\downarrow$

$\Delta n(t=0) = 0$

$D_g \frac{\partial^2 \Delta n}{\partial x^2} = \frac{\partial \Delta n}{\partial t} = G$

$G_1 = \text{generation rate}$

$[G_1] = C^{-1} s^{-1}$

$\downarrow$  Now  $\frac{\partial \Delta n}{\partial t} = 0$  {cause light incident on every  $x$ }

$\Rightarrow \frac{\partial \Delta n}{\partial t} = 0 \quad \left| \Delta n = \text{const.} \right.$

$\text{So, } J_n \text{ & } J_p \text{ are in same direct}$

# For Intrinsic S.C.  $\downarrow$

$E_g \downarrow \quad \epsilon_c \downarrow \quad \epsilon_v \downarrow$

if  $\epsilon > \epsilon_g$ ; EMP generation {optical generation}

\* Also there is Thermal Generation

# Thermal Generation  $\downarrow$

helps in creating intrinsic charge carriers

# Recombination  $\downarrow$

$R = \frac{\Delta n}{T_n}$  Recomb. lifetime

$$\frac{\partial (\Delta n)}{\partial t} = D_g \frac{\partial^2 \Delta n}{\partial x^2} + G_{op} - \frac{\Delta n}{T_n}$$

## RECOMBINATION

$$\begin{aligned} & \text{Direct Recomb. / band gap} & \text{Defect State} \\ & \text{Recombs. via Defect State is easy as compared to Direct Recomb.} \\ & \text{Shockley Read Hall Recomb. (SRH)} \\ & \text{Generation (G)} \quad \text{Recomb. (R)} \\ & \frac{\partial \Delta n}{\partial t} = D_g \frac{\partial^2 \Delta n}{\partial x^2} + G_{op} - R \end{aligned}$$

Recomb. time:-  
Time spent before recomb<sup>1</sup>

∴ let's say  $\frac{\partial^2(\Delta n)}{\partial x^2} = 0 \Rightarrow \left\{ \begin{array}{l} \text{can be achieved} \\ \text{by uniform illumination} \end{array} \right\}$

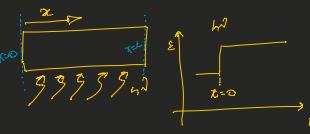
$$\therefore \frac{\partial(\Delta n)}{\partial t} = G_{op} - \frac{\Delta n}{\tau_n}$$

By solving this :-

$$\Delta n(t) = G_{op} \cdot t \left( 1 - e^{-t/\tau_n} \right)$$

Steady State

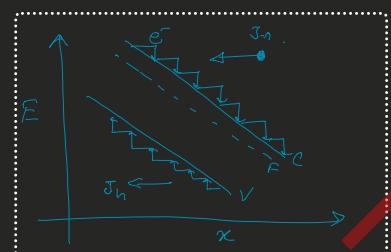
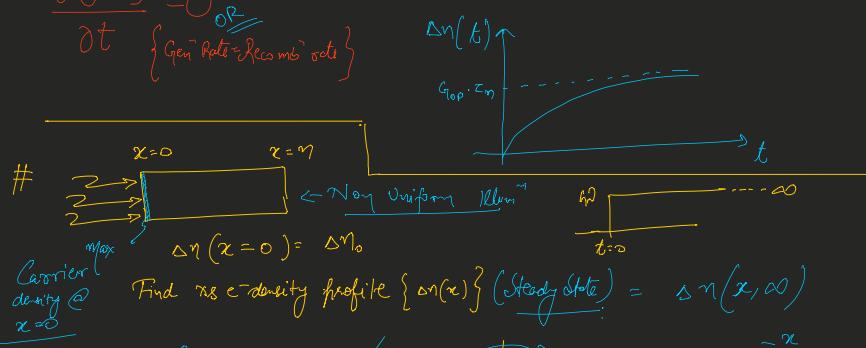
$$\frac{\partial(\Delta n)}{\partial t} = 0 \quad \left\{ \begin{array}{l} \text{Gen. Rate} = \text{Decom. Rate} \\ \text{or} \end{array} \right\}$$



find  $\Delta n(t)$

In most cases,  $\Delta n(t, x)$

We created condition  
in which  $\Delta n(x) = \text{const}$



$A = B$

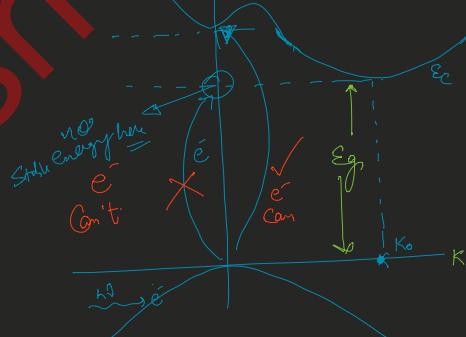
$$\lambda_D = \sqrt{D \cdot \tau_n}$$

Diffusion length

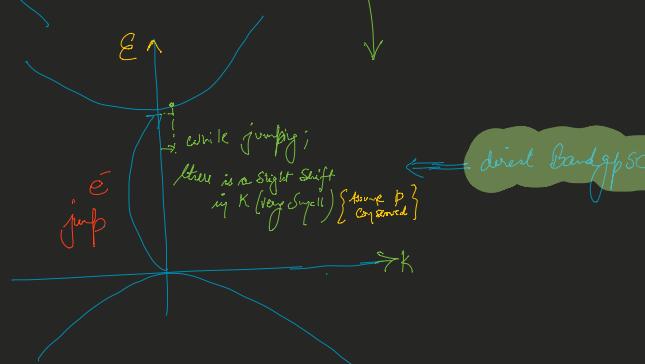
$\Delta n(x) = A e^{-x/\lambda_D}$

$$\Delta n(x) = \Delta n_0 e^{-x/\lambda_D} \quad (\text{from initial load})$$

Quantum Reasoning  
# Photon momentum is small; Energy large  
# Phonon momentum is large; Energy small



Indirect Bandgap  
\* p, E Conserved while jumping  
 $p = \hbar k$



$\eta$ -type  $L = 1 \mu m$

$N_D = 10^{17} \text{ cm}^{-3}$

$M_s = 100 \text{ cm}^2 / V \cdot s$

$K_B T = 26 \text{ meV} \Rightarrow \frac{K_B T}{q} = 26 \text{ mV}$

$N_V(T=300) = 10^{21} \text{ cm}^{-3}$

$N_C = 10^{22} \text{ cm}^{-3}$

$D = M \cdot \frac{K_B T}{q} = 100 \cdot 0.026 = 26 \text{ cm}^2 / \text{s}$

$J = \eta q / M \cdot E$

# SCATTERING

Ionized Impurity Scattering:  $\mu_I = \frac{q}{m^*} C_p$  depends on speed of charge

Both are free if  $q=0$

Phonon Scattering / lattice scattering:  $\mu_p = \frac{q}{m^*} C_p^*$  Phonons & Press waves

Total scattering rate:  $\frac{1}{\tau_{\text{eff}}} = \frac{1}{\tau_I} + \frac{1}{\tau_p} + \dots$

Depends on size of lattice:  $\rightarrow$  depends on  $\Delta r \propto 1/\sqrt{N_A}$  as both donor & acceptor scatter equally

Free doping:  $\rightarrow$  High Rate of Collision  $\Rightarrow$  Smaller mean size of lattice ( $C$ )

$$\mathcal{M} = \frac{q^2 C}{m^*} \quad V_d = \frac{q \epsilon}{m^*} C \quad \text{for hole; } q = +q/(+e) \\ e^- \quad q = -q/(-e)$$

solid only:  $\downarrow$  Electric field (assuming  $C \propto 1/\epsilon$ )  
 $\downarrow$  @ high SF;  $C \propto \frac{1}{\epsilon}$

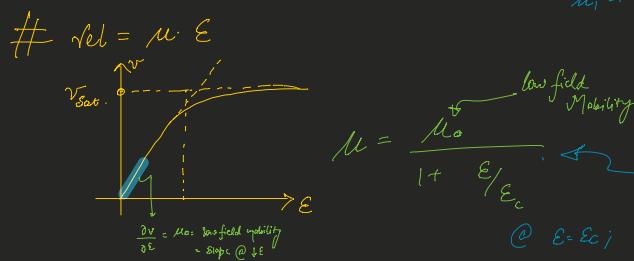
# Temperature Dependency

$T \uparrow \rightarrow$   $\mu_s \propto \frac{1}{T^{3/2}}$  (Gaussian)  $\rightarrow$  more vib  $\rightarrow$  more scatt.  $\rightarrow$  more phonon scatt.  $\downarrow$  less mobility

$T \uparrow \rightarrow$   $C^-$  intrinsic migration fast  $\rightarrow$  interacting time with fixed Cimp.  $\rightarrow$  less scatt.  $\downarrow$  more mobility

At low temp, impurity scattering dominates

At high temp,  $\mu_p \rightarrow$  dominant  $\mu_i \rightarrow$  negligible



$$\mu = \frac{\mu_0}{1 + \frac{E}{E_c}} \quad \text{low field mobility} \quad \text{Empirical relation}$$

@  $E = E_c$ :  $v = \frac{\mu_0 \cdot E_c}{2}$

ideal vel.  $\Rightarrow v = \mu_0 \cdot E_c$

p-type:  $\Delta n(x) = ?$

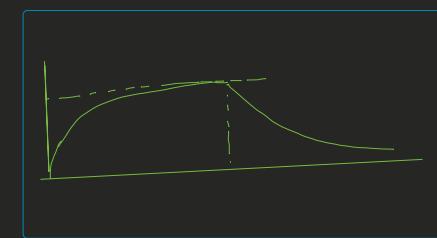
Sol:  $\Delta n(t) = G_1 \cdot \bar{C}_n \left(1 - e^{-t/\bar{C}_n}\right)$  for  $t \in [0, T]$

$\frac{\partial (\Delta n(t))}{\partial t} = D_n \frac{\partial^2 (\Delta n)}{\partial x^2} + G_1 - \frac{\Delta n}{\bar{C}_n}$

for  $t > T$ ;  $G_1 = 0$

$\therefore \frac{\partial (\Delta n(t))}{\partial t} = -\frac{\Delta n}{\bar{C}_n}$

$\Delta n(t) = \Delta n(t=T) \cdot e^{-\frac{t-T}{\bar{C}_n}}$   $\Rightarrow$  for  $t \geq T$   $\left\{ \Delta n(t=T) = G_1 \bar{C}_n \left(1 - e^{-T/\bar{C}_n}\right) \right\}$



# we want faster decay  $\omega_{\text{osc}} \text{ freq} \approx 50 \text{ Hz}$

Layer diode Speed:  $\downarrow$   $\frac{1}{R}$   $\downarrow$   $\frac{1}{C_L}$   $\downarrow$   $\frac{1}{R \cdot C_L}$   $\downarrow$   $\frac{1}{\text{Time to decay}}$

$\Rightarrow$  Diffusion Eqn  $\rightarrow$  Frequency Decay  $\downarrow$

$$\# \frac{\partial \Delta n}{\partial t} = D \frac{\partial^2 \Delta n}{\partial x^2} + G_1 - R$$
 $= D \frac{\partial^2 \Delta n}{\partial x^2} + G_{\text{app}} - \frac{\Delta n}{\bar{C}_n}$ 
 $R = \beta n b = \frac{1}{2}$

p-type:  $\bar{C}_n \approx \frac{1}{P}$

if sc. is p-type;

$$\frac{\partial \Delta n}{\partial t} = D \frac{\partial^2 \Delta n}{\partial x^2} + G_{\text{app}} - \frac{\Delta n}{\bar{C}_n}$$

if majority carrier; they carry small electric field gives large drifts

$\bar{C}_n \approx \frac{1}{P \cdot n^2}$

$\Delta n$  - other diff.  
 $\Delta p$  - maj. drift.

$P = P_0 + \Delta P$   
 $n = n_0 + \Delta n$

Majority Minority

$$\begin{aligned} \mathcal{E} &= -\frac{dV}{dn} \\ &= -\frac{V(x=L) - V(x=0)}{L} \\ &= -\frac{V}{L} \\ &= \frac{d(\epsilon_q(x))}{dn} \\ \mathcal{E} &= \frac{1}{\epsilon_q} \frac{d\epsilon_q}{dn} \end{aligned}$$

Chirish Jain 22b3931

1.  $\nabla \cdot \vec{D} = \rho$   
 2.  $\epsilon \nabla \cdot \vec{E} = \rho$   
 $\rightarrow \nabla \cdot \vec{E} = \frac{\rho}{\epsilon}$   
 3.  $\nabla V = -\frac{\rho}{\epsilon}$   
 $\Rightarrow \nabla^2 V = -\frac{\rho}{\epsilon} = \frac{2}{\lambda} = -\frac{\rho}{\epsilon}$

4.  $\vec{E} = -\nabla V$   
 only if  $\rho$  part  
 $\rightarrow \vec{D} = \epsilon \vec{E}$   
 Electric Resp Vector

Poisson's Eqn:

for minority;  $\Delta n(x) = \Delta n_0 e^{-x/l}$

" majority;  $\Delta p \sim \frac{1}{\beta \eta} \quad \eta \downarrow \propto \uparrow \left\{ \begin{array}{l} \text{lifetime of holes} \uparrow; \text{they work} \\ \text{again in majority} \end{array} \right.$

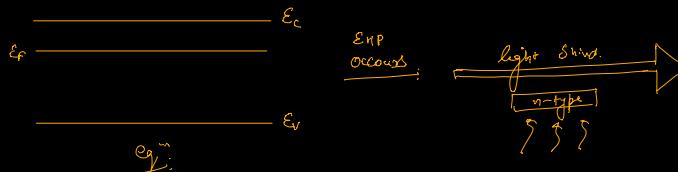
$$\frac{\partial \Delta p}{\partial x} = D_p \frac{\partial^2 p}{\partial x^2} + G_{op} - \frac{\Delta p}{\tau_p}$$

Diff. hole density  $\therefore$  if p-type tends drift with dominance  
Diff.  $\propto$  grad.

Fermi's Golden Rule

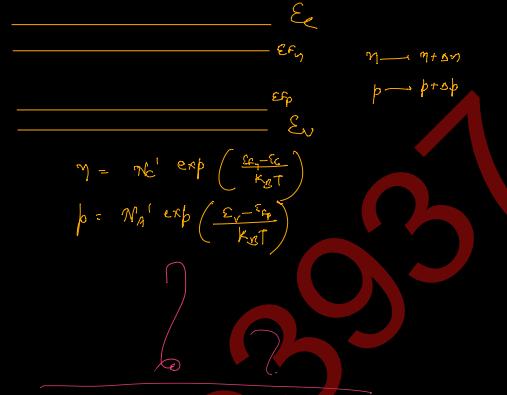
$$R \propto n; p = \text{Const.}$$
$$R \propto p; \eta = \text{Const.}$$
$$R = \beta n p \quad \boxed{C_V = \frac{1}{\beta N_A T}} \quad p = \text{Const.}$$

# Quasi Fermi level.



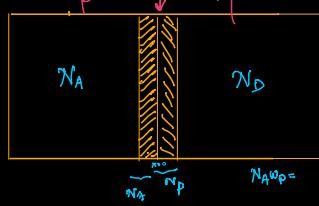
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Majority carrier



# DIODE

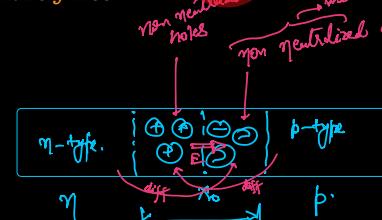
@  $x=0; N_D=N_A$   
at doping = 0



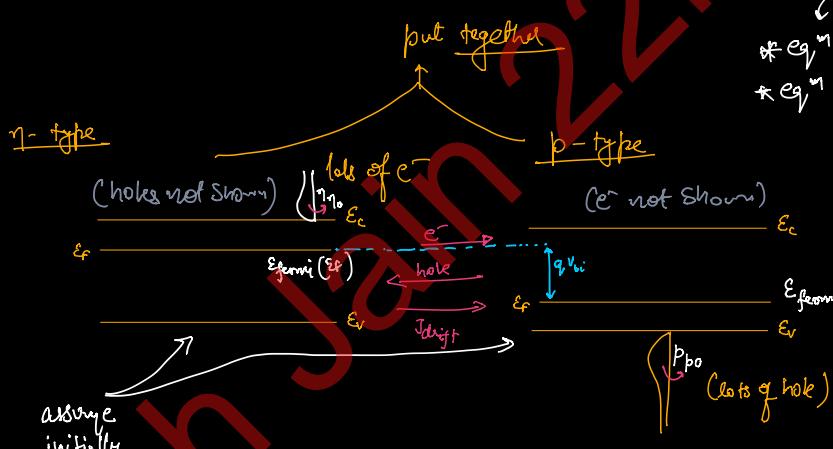
$$N_{DWA} = N_A W_p$$

$$\text{as you charged couple is given,} \quad p = N_A \quad \left| \begin{array}{l} N_A = N_A e^{-qV_m} \\ N_D = N_D e^{-qV_m} \end{array} \right. \quad \left| \begin{array}{l} N_D = N_D e^{-qV_m} \\ N_D = N_D e^{-qV_m} \end{array} \right.$$

Quasi free electrons: very small interaction with the electrons. But not entirely free



\* Total charge on both sides but of diff sign  
Same on both sides but of diff sign  
This region is depleted of free charges (free = non-conducting face)  
Hence also k/a depleting Region



(after all impurities are ionized)

\*  $e^-$  loc. on "n" side:  $n_{no} = N_A^1$   
\*  $p^+$  loc. on "p" side:  $p_{po} = N_D^1$

@  $eq^m$ ;  $J_n = J_p = 0$  (no net current)

\* Built-in Pot. Energy Barrier =  $qV_{bi}$

$$qV_{bi} = \Phi_p - \Phi_n$$

\* for unequal doping; import of the space charge is in the region with lighter doping

$$V=0 \quad ; \quad J=0 = J_n + J_p$$

app. voltage:  $\therefore J_n \neq 0 \quad J_p = 0$

$$E_F = \text{Const.} @ eq^m$$

$$J_n = q_r \left( \eta \mu_n E + \frac{D}{\partial x} \right) \quad \left| \frac{D}{\mu} = \frac{k_B T}{q^2} \right.$$

$$J_n = q_r \mu_n \left[ \eta E + \frac{KT}{q} \frac{\partial n}{\partial x} \right]$$

both are pos<sup>n</sup> dependent.

$$\Rightarrow \frac{\partial n}{\partial x} = \frac{N_A^1}{k_B T} \cdot \exp \left( \frac{E_F - E_C}{k_B T} \right) \cdot \left[ \frac{\partial E_F}{\partial x} - \frac{\partial E_C}{\partial x} \right]$$

$$\frac{1}{qV} \frac{\partial E_C}{\partial x} = E$$

$$= \frac{n}{k_B T} \left[ \frac{\partial E_F}{\partial x} - qE \right]$$

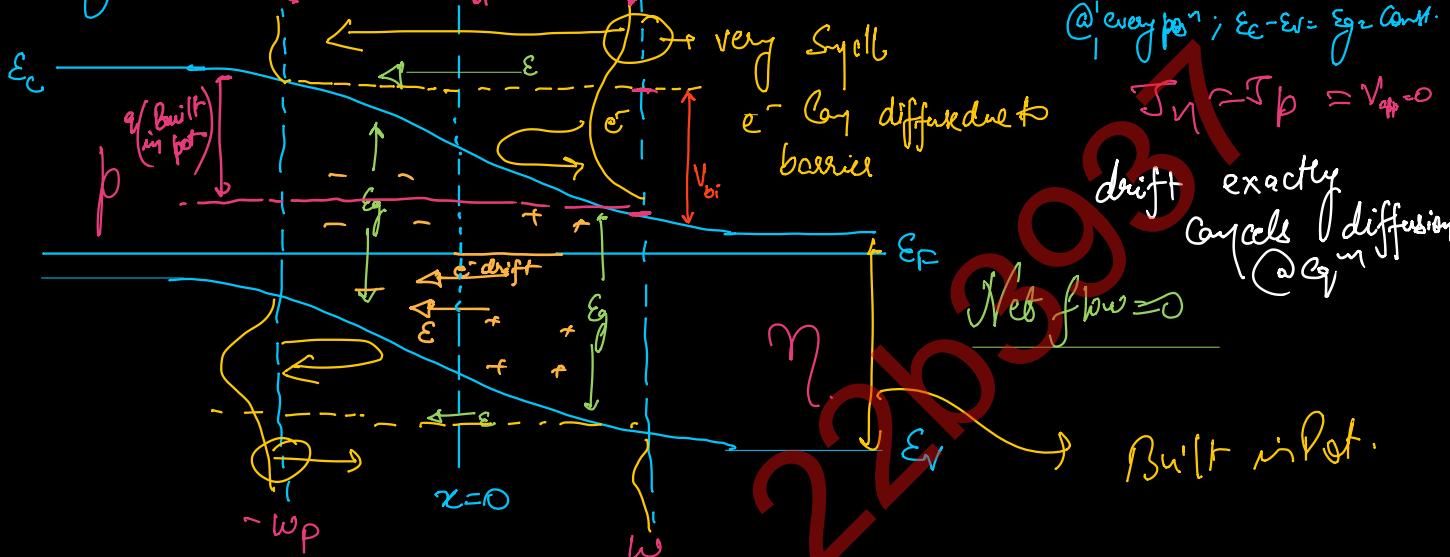
Hence:  $J_n = q_r \mu_n \eta \left( \frac{\partial E_F}{\partial x} \right)$

↓

if  $\epsilon_{eff} = \frac{1}{q} \frac{\partial \epsilon_r}{\partial n}$   $\Rightarrow I_n = \underbrace{\mu_n \cdot n \cdot q \cdot \epsilon_{eff}}_{drift \cdot Current \ of \ e^-}$

$\therefore @ e_g^m$   $\frac{\partial \epsilon_r}{\partial n} = 0$

Far away from the interface; Nothing has changed



Intrinsic SiC. Potential Barrier / Built in pot<sup>7</sup> ( $V_{bi}$ ) / Cat-M voltage

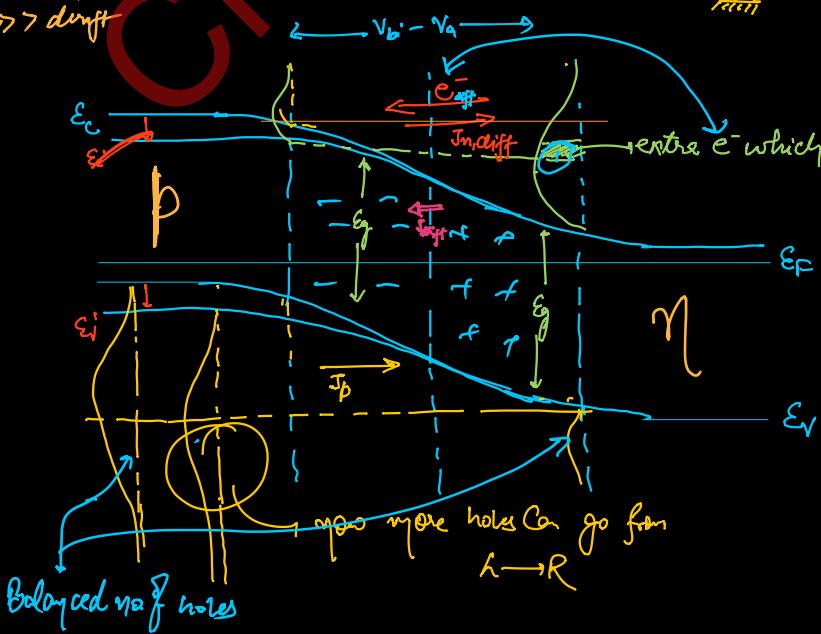
⇒ Forward Bias Applied

diff > drift:

$$\text{New barr.} = q(V_{bi} - V)$$

$$|w_n| + |w_p| = \text{Depletion Width}$$

\* In forward bias; more e- in p well as built in pot. ↓; hence diff > drift

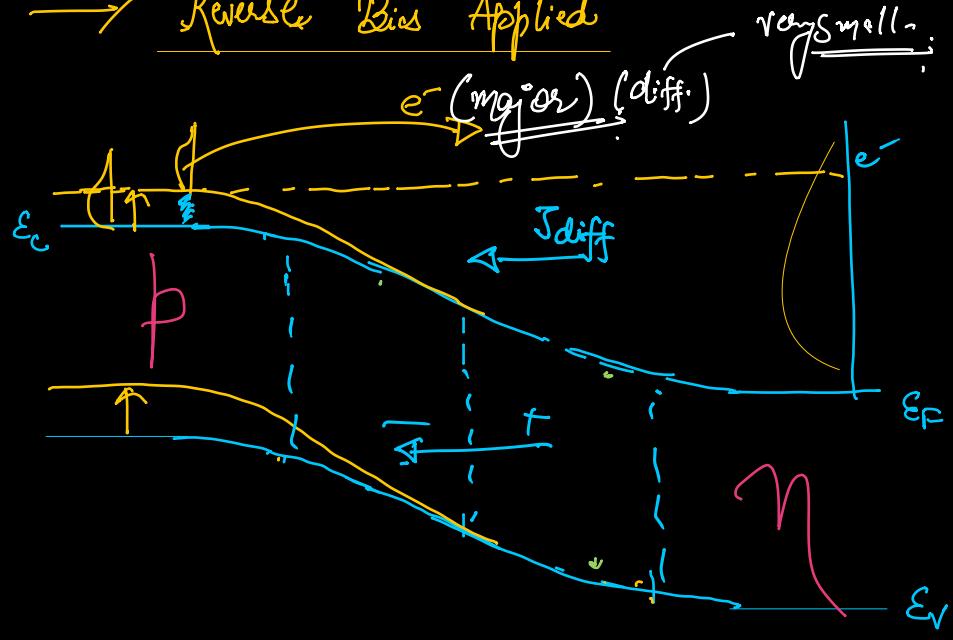


( $V_{bi}$  is ↓); So some e- can diffuse from n → p

Note  
Resistivity  $\propto$   $\frac{1}{\text{Conc. of free carriers}}$

Recall:- Depletion region has no free carrier

$\Rightarrow$  Reverse Bias Applied

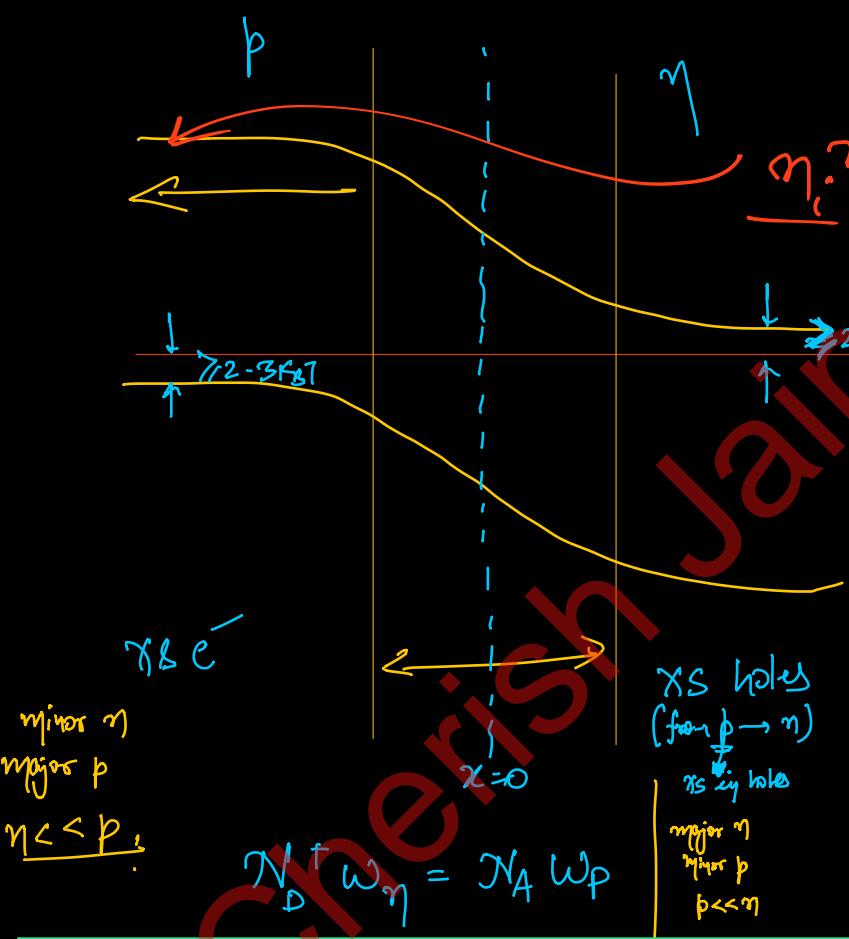


$$\left\{ \begin{array}{l} J_{minority} > J_{majority} \\ \text{across very small.} \end{array} \right.$$

$$\text{New curr} = q(V_{bi} + V)$$

$$J = J_{n,diff} + J_{p,diff}$$

$J$  is small.

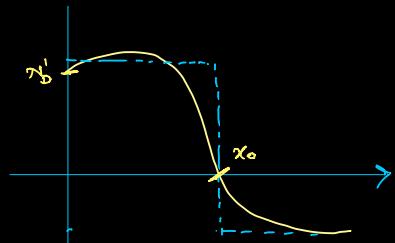
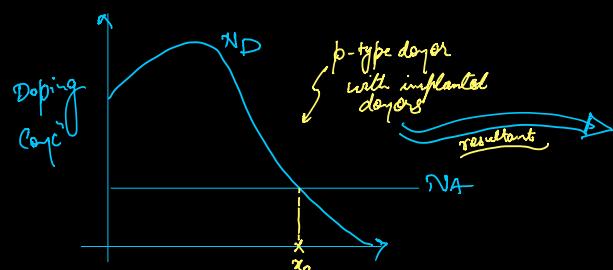
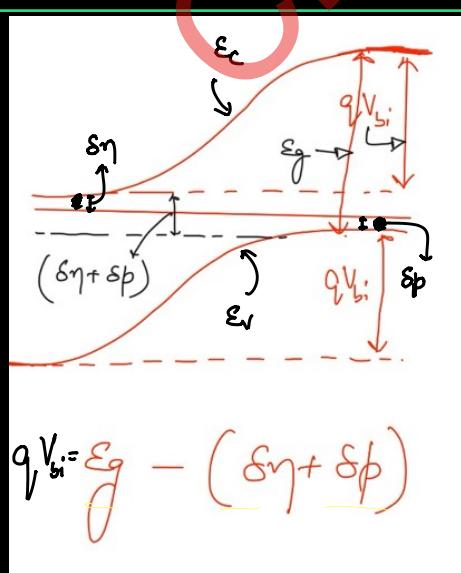


- ① Quasi-neutral region  
region far away from interface have  $\epsilon \approx 0$

- ② Abrupt + Junction :-  
just outside Junction  $n$  &  $p$  Starts  
Abruptly

- ③ Boltzmann App. Valid.

- ④ Low Level injection



$$* \text{ On } n\text{-side; } N_D' = N_D - N_A = \text{Constant} \quad * \text{ On } p\text{-side; } N_A' = N_A - N_D = \text{Constant}$$

$$\rightarrow n_{n_0} = N_D'$$

$\hookrightarrow e.g. n \text{ conc in } n \text{ side}$

$$\rightarrow p_{p_0} = N_A'$$

$\hookrightarrow e.g. n \text{ hole conc in } p \text{ side}$

$$\delta\eta = E_c - E_F = kT \ln\left(\frac{N_c}{n}\right) = kT \ln\left(\frac{N_c}{N_D}\right) \quad \text{why not } N_c'$$

$$n = N_c' \exp\left(-\frac{(E_c - E_F)}{kT}\right)$$

$$p = N_V' \exp\left(-\frac{(E_F - E_V)}{kT}\right)$$

Degenerate semiconductors contain high level of doping, with significant interaction between dopant atoms. The interaction results in the formation of donor/acceptor bands rather than discrete energy levels. These impurity bands can overlap with the corresponding band edges of conduction or valence bands.

The convention is that for degenerate semiconductors that Fermi level is present close to the conduction and valence band edges, typically in the range of  $3kT$  from the band edges.

\* if material is degenerately doped; we take Fermi level to be at the band edge

$$\delta\eta = 0 \rightarrow n_{\text{side}}, \text{ degenerate}$$

$$\text{Similarly } \delta p = kT \ln\left(\frac{N_V}{N_A}\right) \rightarrow p_{\text{side}}, \text{ non-degen.}$$

$$= 0 ; p_{\text{side}} ; \text{degen.}$$

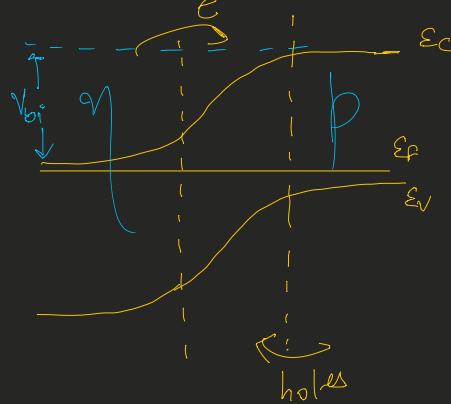
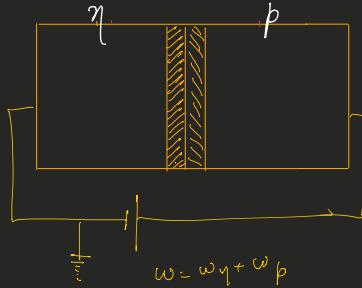
$$\delta n / \delta p \ll 2 - 3 kT$$

$$\text{Hence; } qV_{bi} = E_g - kT \ln\left(\frac{N_c}{N_D}\right) - kT \ln\left(\frac{N_V}{N_A}\right)$$

## Fermi level

① when forward biased:  $\omega(\omega_n + \omega_p) \downarrow$

② For away;  $n \propto n_i \propto p_i \propto p$



\*  $T \uparrow \Rightarrow V_{bi} \downarrow$

\*  $T \uparrow \Rightarrow n_i \uparrow$

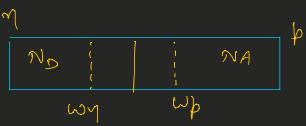


$$N_D \ll n_i \Rightarrow n_i \gg N_D$$

$$N_A \ll n_i \Rightarrow p_i \gg N_A$$

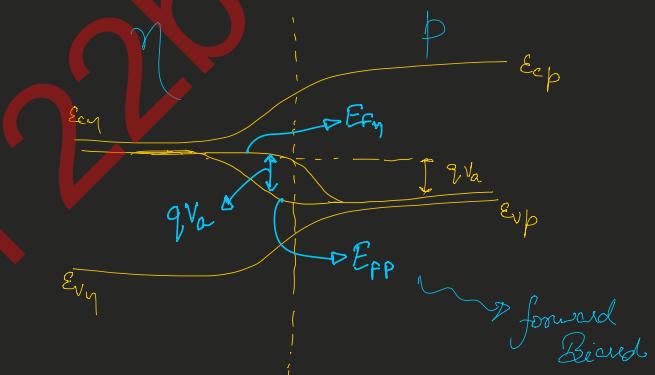
So  $n \approx n_i$  &  $p \approx p_i$

$$\checkmark \text{ Diode } @ E_V \text{ (} V_a = 0 \text{)}$$

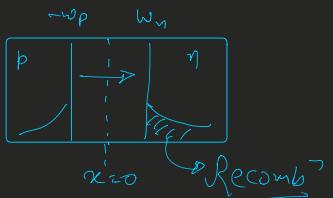


$$N_D \omega_n = N_A \omega_p$$

\* Due to quasi-neutral region;  
beyond depletion region;  
 $n \propto n_i$  &  $p \propto p_i$



→ Reverse Biased



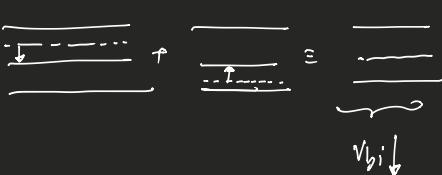
if  $V_{bi} = 0$  | diode acts as a resistor

Q why  $V_{bi} \downarrow$  as  $\text{Temp} \uparrow$

Sol: @ RT  $\rightarrow n \propto p \propto$



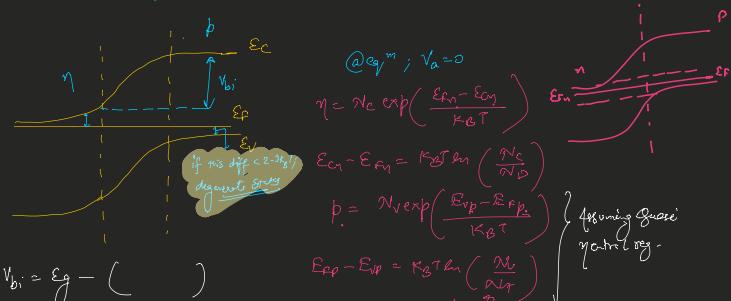
@ High T  $\Rightarrow n \propto p \propto$



Junction

$N_D(x_0 - x_A) = N_A(x_p - x_0)$

$N_D \omega_{\eta} = N_A \omega_p$



$$V_{bi} = Eg - \left( \dots \right)$$

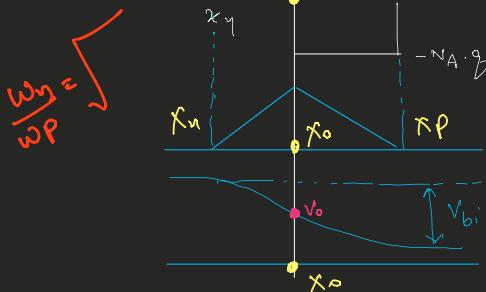
$$\eta_i = \sqrt{N_c N_v} \exp\left(-\frac{E_g}{2 k_B T}\right)$$

$$V_{bi} = \frac{k_B T}{q} \ln\left(\frac{\eta_i N_D}{\eta_i^2}\right)$$

$$\Rightarrow q V_{bi} = Eg - (Eg + \epsilon_p)$$

$$\begin{aligned} q V_{bi} &= Eg - k_B T \left[ \ln\left(\frac{N_c}{N_D} + \ln\left(\frac{N_v}{N_A}\right)\right) \right] \\ &= Eg - k_B T \ln\left(\frac{N_v}{N_A N_D}\right) \\ &= Eg - k_B T \ln\left(\frac{\eta_i^2}{N_A N_D}\right) + Eg \\ &= \frac{k_B T}{q} \ln\left(\frac{N_A N_D}{\eta_i^2}\right) \end{aligned}$$

\* max obtainable  
Built-in potential =  $Eg$

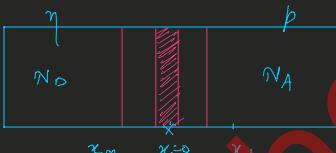


$$W = w_n + w_p = \left[ \frac{2e V_{bi}}{q} \left( \frac{1}{N_A} + \frac{1}{N_D} \right) \right]^{\frac{1}{2}} = |\tau_0 \tau_n| + |\tau_0 - \tau_p|$$

On the n side the result is

$$\mathcal{E}(x) = \frac{N'_D}{\epsilon} (x - x_n) \quad x_n \leq x \leq x_0$$

$$\mathcal{E}(x) = \frac{N'_A}{\epsilon} (x_p - x) \quad x_0 \leq x \leq x_p$$



both at n side  
 $N_D > N_A$   
 $w_n \ll w_p$   
 $\eta \downarrow$  electron density.  
 $\eta_{po} \uparrow$  hole  $\epsilon_{pn}$  density.

$$\eta_{po} = N_C \exp\left(\frac{E_{Fn} - E_{Cn}}{k_B T}\right) \quad (2)$$

$$\eta_{po} = \eta_{po} \exp\left(-\frac{q |V_{bi}|}{k_B T}\right)$$

Often; 1 Side is degenerately doped,  
so nomenclature is that  $n^+ p$   
junction has n side degenerate left  
Side non degenerate. {  $p^+ n \rightarrow$  opposite }  
Pn junction:-  $q V_{bi} = Eg - k_B T \ln \frac{N_c}{N_D} - \ln \frac{N_v}{N_A}$

$$n^+ p \text{ junction: } q V_{bi} = Eg - k_B T \ln \frac{N_v}{N_A}$$

$$p^+ n \text{ junction: } q V_{bi} = Eg - k_B T \ln \frac{N_c}{N_D}$$

for a non deg. S.C.  $\eta_i^2 = N_c N_v e^{-E_g/k_B T}$

$$Eg = k_B T \ln\left(\frac{N_c N_v}{\eta_i^2}\right)$$

THUS

$V_{bi} = \frac{kT}{q} \ln \frac{N'_D N'_A}{n_i^2}$	pn junction
$V_{bi} = \frac{kT}{q} \ln \frac{N'_V N'_A}{n_i^2}$	p <sup>+</sup> n junction
$V_{bi} = \frac{kT}{q} \ln \frac{N'_C N'_A}{n_i^2}$	n <sup>+</sup> p junction

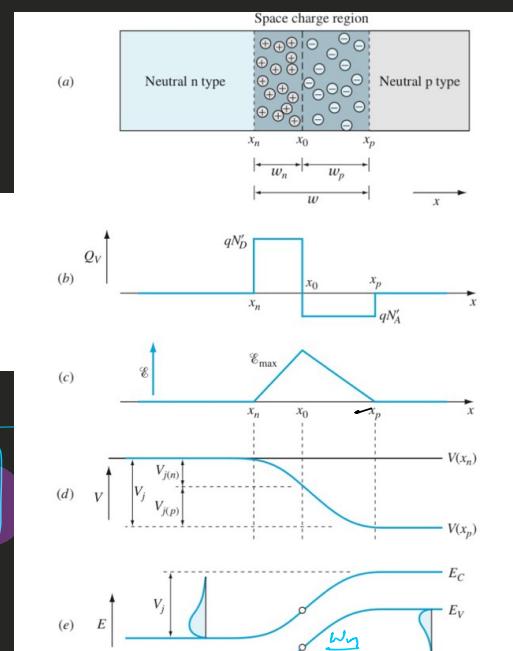


Figure 5.14 A prototype homojunction: (a) the physical diagram; (b) the distribution of charge; (c) the electric field, obtained by integrating the charge; (d) the voltage, obtained by integrating the field; (e) the energy band diagram, with the same shape as the voltage but Inverted. The energy band diagram of (e) is for the device reverse-biased.

$$V(x) - V(x_n) = -\frac{q N'_D}{2\epsilon} (x - x_n)^2 \quad x_n \leq x \leq x_0$$

$$V(x_p) - V(x) = -\frac{q N'_A}{2\epsilon} (x_p - x)^2 \quad x_0 \leq x \leq x_p$$

$$\frac{V(x_n) - V(x_0)}{V(x_0) - V(x_p)} = \frac{V_j^n}{V_j^p} = \frac{N'_D w_n^2}{N'_A w_p^2}$$

Note  $\rightarrow qV_{bi}, \text{max} \sim E_g$  \* @ eq<sup>m</sup>;  $E_{FP} = E_{Fn}$

# Density of States ( $N_C, N_V$ ) depends upon material property. Since  $n \propto$   
 p type have same material; they are same on both sides.  $N_{Cn} \approx N_{Cp} / N_{Vn} = N_{Vp}$

# in forward bias;  $qV_{bi} \rightarrow q(V_{bi} - V_a)$

$$|E_{CP} - E_{CV}| = |qV_{bi}|$$



$$p_n = p_{p_0} \exp\left\{-\frac{q(V_{bi} - V_a)}{kT}\right\}$$

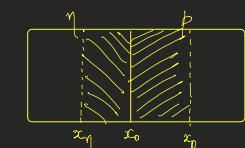
$$n_p = n_{n_0} \exp\left\{-\frac{q(V_{bi} - V_a)}{kT}\right\}$$

$$\Delta n_p (x=x_p) = n_p - n_{p_0} = n_{n_0} \exp\left\{-\frac{q(V_{bi} - V_a)}{kT}\right\} - n_{n_0} \exp\left\{-\frac{qV_{bi}}{kT}\right\}$$

$$\Delta n_p (x=x_p) = n_{n_0} \exp\left(-\frac{qV_{bi}}{kT}\right) \left\{ \exp\left(\frac{qV_a}{kT}\right) - 1 \right\}$$

$$\begin{aligned} n_{n_0} &= N_C \exp\left(\frac{E_{Fn} - E_{Cn}}{k_B T}\right) \\ n_{p_0} &= N_C \exp\left(\frac{E_{FP} - E_{CP}}{k_B T}\right) \\ &= n_{n_0} \exp\left(-\frac{q|V_{bi}|}{k_B T}\right) \end{aligned}$$

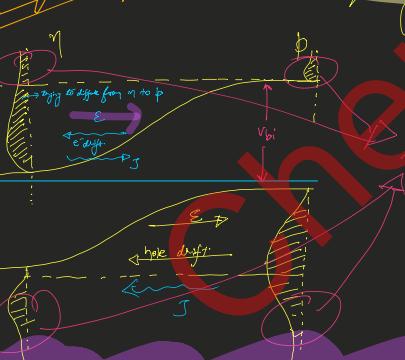
$$\begin{aligned} \text{Similarly: } p_{p_0} &= N_V \exp\left(\frac{E_{Fn} - E_{FP}}{k_B T}\right) \\ p_{p_0} &= N_V \exp\left(-\frac{q|V_{bi}|}{k_B T}\right) \end{aligned}$$



$$N_D \rightarrow N_D^+ + e^-$$

$$N_A + e^- \rightarrow N_A^-$$

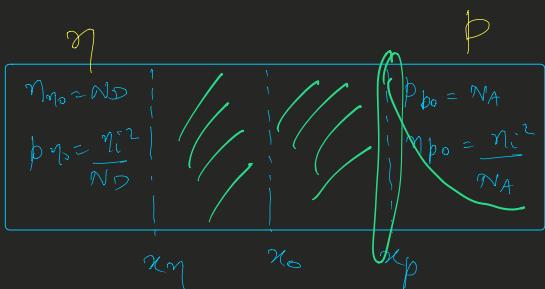
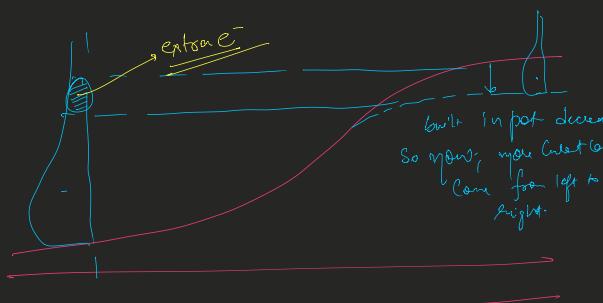
$E_m$ !



Width of the depletion layer is affected by built-in potential. If built-in potential dec, width decreases. It happens in forward bias.

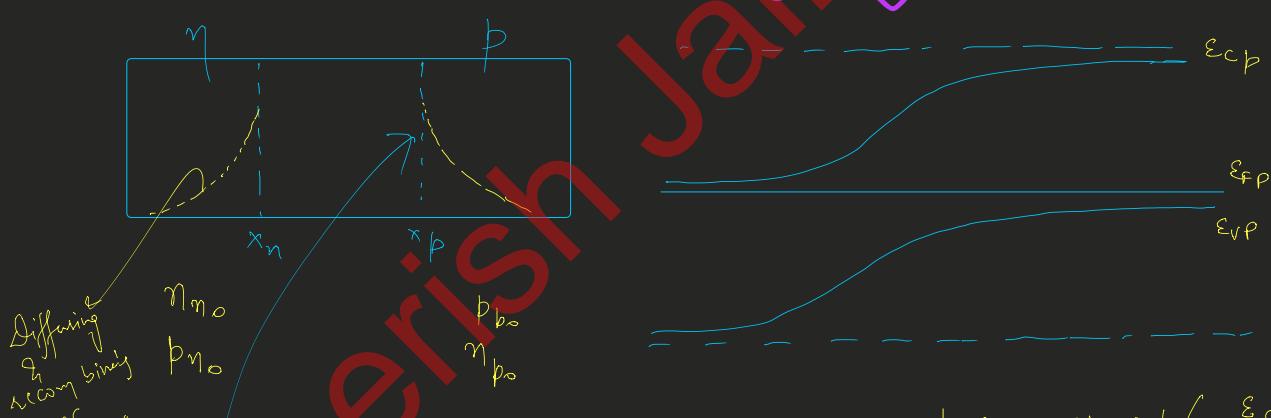
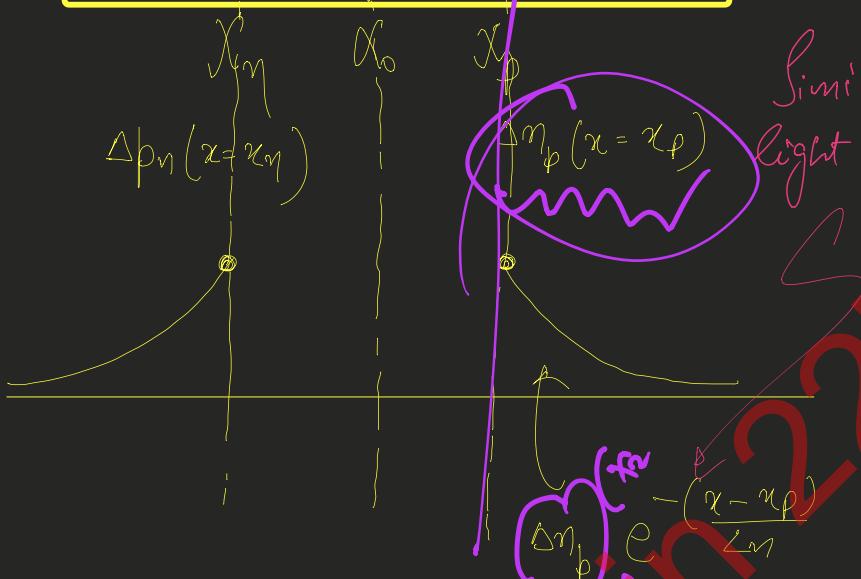
$$\begin{aligned} \nabla \cdot D &= P \\ \nabla \cdot \epsilon_F &= P_S x \\ \frac{\partial \epsilon}{\partial x} &= \frac{P}{\epsilon} = \frac{qN_D}{\epsilon} \quad \rightarrow \text{Charge Density} \\ \epsilon &= \frac{qN_D}{\epsilon} x + k \\ \epsilon(x=x_0) &= 0 \\ \epsilon(x) &= \frac{qN_D}{\epsilon} (x-x_0) \end{aligned}$$

Note: Electrostatics is instantaneous



$$\Delta n_\phi = n_{n_0} \left[ e^{\frac{qV_a}{kT}} - 1 \right] \cdot e^{-\frac{qV_{bi}}{kT}}$$

$$\Delta n_p(x = x_p) = n_{m_0} \left( e^{\frac{qV_b}{kT}} - 1 \right) e^{-\frac{qV_b}{kT}}$$



$\text{at } e_g^m; n_{N_0} = N_D$

$$p_{N_0} = \frac{n_i^2}{N_D}$$

$$n_{m_0} = N_C \exp\left(\frac{E_{Fm} - E_{Cm}}{k_B T}\right)$$

$$n_{p_0} = N_C \exp\left(\frac{E_{FP} - E_{CP}}{k_B T}\right) = n_{m_0} \exp\left(-\frac{q|V_{bi}|}{k_B T}\right)$$

Similarly if  $p_{p_0} = N_V \exp\left(\frac{E_{VP} - E_{FP}}{k_B T}\right)$

\* Subscript tells side whether  $p$  or  $n$

$$p_{N_0} = N_V \exp\left(\frac{E_{VN} - E_{FN}}{k_B T}\right)$$

$$= p_{p_0} \exp\left(-\frac{q|V_{bi}|}{k_B T}\right)$$

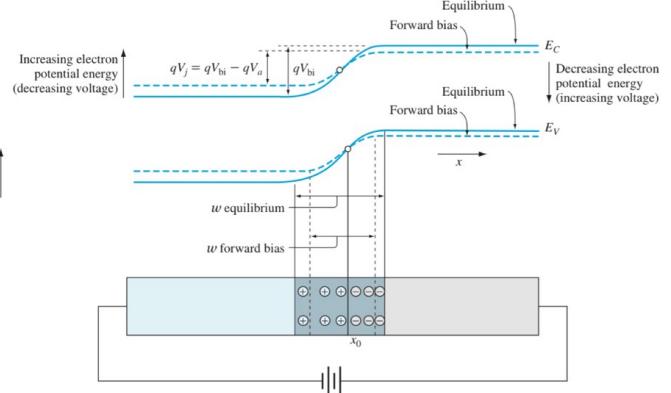


Figure 5.7 The space charge region width under equilibrium and forward bias, and the corresponding energy band diagrams.

$n_{m_0} = N_C \exp\left(\frac{E_{Fn} - E_{Cm}}{k_B T}\right)$

$n_{p_0} = N_C \exp\left(\frac{E_{FP} - E_{CP}}{k_B T}\right) = n_{m_0} \exp\left(-\frac{q|V_{bi}|}{k_B T}\right)$

$n_{N_0} = N_V \exp\left(\frac{E_{VN} - E_{FP}}{k_B T}\right)$

$n_{p_0} = n_{N_0} \cdot \exp\left(-\frac{q|V_{bi}|}{k_B T}\right) = n_{p_0}$

$$n_{p_0} = N_C \cdot \exp\left(-\frac{E_{CP} - E_{FP}}{k_B T}\right)$$

$$n_{N_0} = N_C \cdot \exp\left[-\frac{E_{CN} - E_{FN}}{k_B T}\right]$$

$$n_{N_0} = N_C \cdot \exp\left[-\frac{(E_{CN} + qV_{bi}) - E_{FN}}{k_B T}\right]$$

$$n_{p_0} = n_{N_0} \cdot \exp\left(-\frac{q|V_{bi}|}{k_B T}\right) = n_{p_0}$$

$$n_{p_0} = n_{N_0} \cdot e^{-\frac{q|V_{bi}|}{k_B T}}$$

$E_{CP}$   $E_{FP}$

(a) Forward Bias:

$$\eta_p = \eta_{p_0} \cdot e^{-\frac{q(V_b - V_a)}{kT}}$$

$$\Delta n_p = \eta_p - \eta_{p_0} = \eta_{p_0} \left( e^{-\frac{qV_b}{kT}} - 1 \right)$$

$$\Delta n_p = \eta_{p_0} \left( e^{-\frac{qV_a}{kT}} - 1 \right)$$

*this is max part*

$$\frac{\partial (\Delta n_p)}{\partial x} = D \frac{\partial^2 (\Delta n_p)}{\partial x^2} - \frac{\Delta n_p}{L_n}$$

(b) Steady State;  $\frac{\partial}{\partial x} (\Delta n_p) = 0$

Hence; @  $x_p$ ;  $\frac{-(x - x_p)}{L_n}$

$$\Delta n_p = \Delta n_p (x = x_p) e^{-\frac{(x - x_p)}{L_n}} ; L_n = \sqrt{D_n \tau_n}$$

At  $x = x_p$ ;

$$J_n, \text{diff} = ?$$

$$J_{n,\text{diff}} = D_n \cdot q \cdot \frac{\partial}{\partial x} (\Delta n_p) \Big|_{x=x_p}$$

$$= \frac{q D_n}{L_n} \Delta n_p (x = x_p)$$

$$= \frac{q D_n}{L_n} \cdot \eta_{p_0} \left( e^{-\frac{qV_a}{kT}} - 1 \right)$$

$$J_{p,\text{diff}} = \frac{q D_p k_{B T_0}}{L_p} \cdot \left( e^{-\frac{qV_a}{kT}} - 1 \right)$$

$$\text{Total } J_{\text{diff}} = J_{n,\text{diff}} + J_{p,\text{diff}} = \left[ q \left( e^{-\frac{qV_a}{kT}} - 1 \right) \right] \left[ \frac{D_n \cdot \eta_{p_0}}{L_n} + \frac{D_p \cdot k_{B T_0}}{L_p} \right]$$

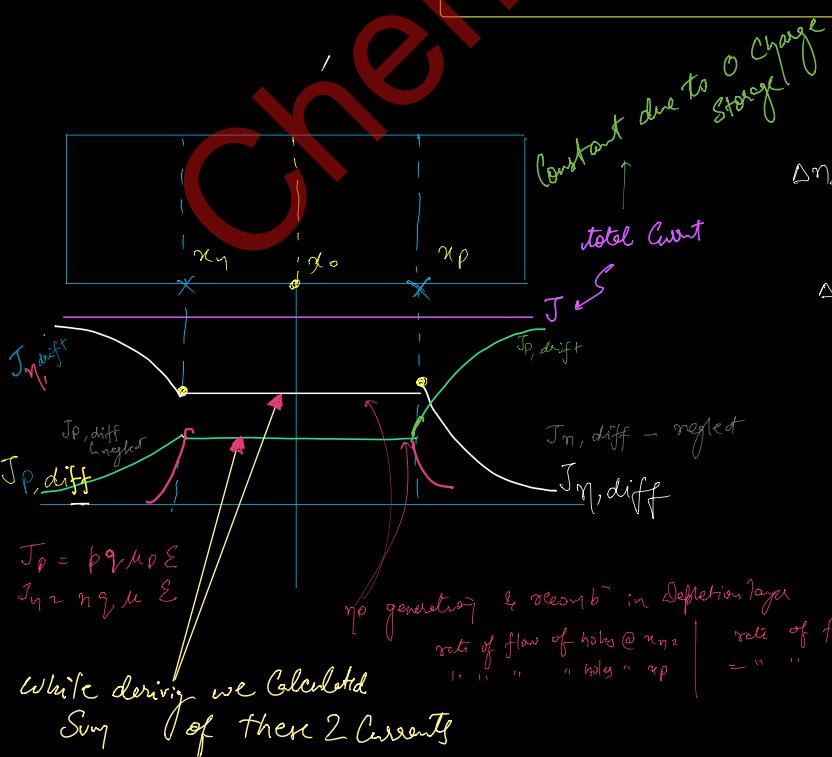
$$J = J_0 \left( e^{-\frac{qV_a}{kT}} - 1 \right)$$

we have only considered diffusion current because in graph we chose depletion area in which  $i = \text{const}$  & they summed up

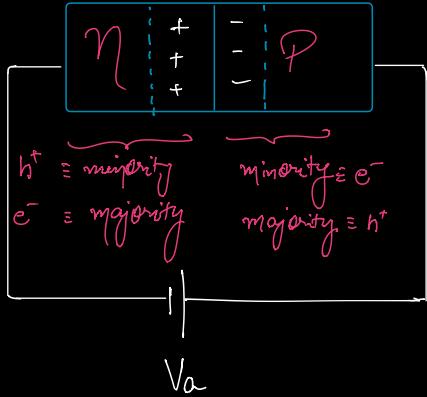
$$J_{p,\text{diff}} \Big|_{x=x_n} = J_{p,\text{drift}} \Big|_{x=x_p}$$

AND

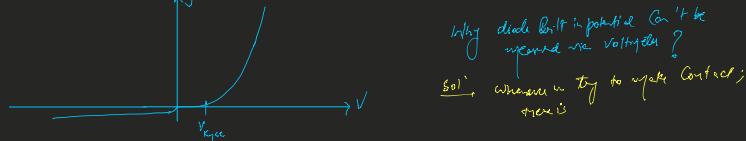
$$J_{n,\text{diff}} \Big|_{x=x_p} = J_{p,\text{drift}} \Big|_{x=x_n}$$



## # DIODE CURRENT eq<sup>n</sup>



$$\# \text{Final Diode Eqn} \rightarrow J = J_0 \left( e^{\frac{qV_{bi}}{kT}} - 1 \right) \quad \left\{ J-V \text{ characteristics of the Diode} \right\}$$



why diode built-in potential can't be increased w.r.t. voltage?  
So, whenever we try to reverse bias, there is

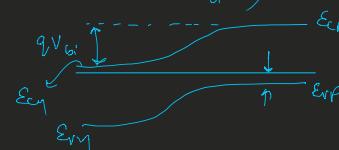
$$\# n_D = 10^{18} \text{ cm}^{-3}$$

$$p_{no} = 10^{17} \text{ cm}^{-3}$$

$$p_{po} = N_A = 10^{18} \text{ cm}^{-3}$$

$$n_{pi} = \frac{n_i^2}{p_{po}} = 1.21 \times 10^2 \text{ cm}^{-3}$$

$$qV_{bi} = k_B T \ln \left( \frac{N_A N_D}{n_{pi}^2} \right) = 0.3 \text{ eV}$$



given

$$kT = 0.026 \text{ eV}$$

$$m_n = 300 \text{ cm}^2/\text{V.s}$$

$$m_p = 100 \text{ cm}^2/\text{V.s}$$

$$\epsilon_{si} = 11.0$$

$$\epsilon_0 = 8.85 \times 10^{-12} \text{ F/cm}$$

$$L_N = 200 \mu\text{m}$$

$$L_P = 100 \mu\text{m}$$

$$\epsilon_{en} - \epsilon_{hp} = k_B T \ln \left( \frac{N_C}{N_{no}} \right) = 0.146 \text{ eV}$$

$$\epsilon_{hp} - \epsilon_{en} = k_B T \ln \left( \frac{N_V}{p_{po}} \right) = 0.088 \text{ eV}$$

$\downarrow$  both  $> 2-3 \text{ eV}$   
Fowler-Nordheim  
approximation valid

### # Width of Depletion Region

$$W = \sqrt{\frac{2qV_{bi}}{q}} \left( \frac{1}{N_A} + \frac{1}{N_D} \right)^{1/2}$$

$$W = 0.2 \times 10^{-4} \text{ cm} = 0.2 \mu\text{m}$$

$$N_D W = N_A W$$

$$\frac{W_N}{W_P} = \frac{N_A}{N_D} \Rightarrow W_N = \frac{N_A}{N_A + N_D} W = 0.18 \mu\text{m}$$

$$\epsilon_{px} = \frac{2V_{bi}}{W} = \frac{2 \times 0.3}{0.2 \times 10^{-4}} \text{ V/cm} = 3 \times 10^4 \text{ V/cm}$$

$$D_N = \frac{k_B T}{e} \mu_N = 7.8 \text{ cm}^2/\text{s}$$

$$D_P = 2.6 \text{ cm}^2/\text{s}$$

$$C_N = \sqrt{D_N Z_N} \Rightarrow Z_N = \frac{C_N^2}{D_N} = \frac{(200 \times 10^{-9})^2}{7.8} = 5.1 \mu\text{s}$$

$$T_D = 3.8 \mu\text{s}$$

$$J_0 = q \left( \frac{D_N n_{po}}{Z_N} + D_P p_{no} \right)$$

$$= 6.54 \text{ PA/cm}^2$$

High level injection

the state where the number of minority carriers generated is small compared to the majority carriers of the material.

$$\boxed{\text{Now, we applied } V_a = 0.8 \text{ V} \mid A = 10^{-6} \text{ cm}^2 \quad \{ 10 \mu\text{m} \times 10 \mu\text{m} \}}$$

$$J = J_0 \left( e^{\frac{qV_T}{kT}} - 1 \right) = 6.54 \left( e^{\frac{0.8}{0.026}} - 1 \right) \text{ PA/cm}^2$$

$$= 6.54 \left( 2.3 \times 10^{12} - 1 \right)$$

$$= 150 \text{ A/cm}^2$$

$$I = JA$$

$$= 150 \times 10^{-6} \text{ A}$$

$$\text{from } \Delta n_p \approx n_{po} \left( e^{\frac{qV_T}{kT}} - 1 \right)$$

$$= 1.2 \times 10^2 \times 2.3 \times 10^{12} \text{ cm}^{-3}$$

$$= 2.8 \times 10^{15} \text{ cm}^{-3}$$

$$\Delta p_n = p_{no} \left( e^{\frac{qV_T}{kT}} - 1 \right)$$

$$= 1.2 \times 10^3 \times 2.3 \times 10^{12} \text{ cm}^{-3}$$

$$= 2.8 \times 10^{16} \text{ cm}^{-3}$$

low level injection

$\Delta n_p \ll n_{po}$

$\Delta p_n \ll p_{no}$

Assumptions made by last guest

- ① Low level injection
  - ② Abrupt junction
  - ③ Depletion Approximation (Guarded beyond borders)
- 

other profiles



$$\therefore J = 150 \text{ A/cm}^2 \\ = q N_{n_0} u_n \propto n$$

$$E = \frac{150}{1.6 \times 10^{-19} \times 10^7 \times 300} = 31.25 \text{ V/cm} \ll \ll \ll E_{max} (3 \times 10^4 \text{ V/cm})$$

Validation of guard region

if  $V_a = 0.8 \text{ V}$  ;

$$J = J_0 (e^{V_a / V_T} - 1) \\ = 6.54 (e^{0.026} - 1) \text{ A/cm}^2 \\ = 3.3 \times 10^{-5} \text{ A/cm}^2$$

$$\Delta p_n = p_{n_0} (e^{V_a / V_T} - 1)$$

$$= 1.21 \times 10^{-2} \times 5 \times 10^{-16}$$

$$= 6 \times 10^{-19} \text{ C/m}^2$$

→ high level injection (minority often biasing of  $V_a = 1 \text{ V}$ )

$$E = 6.8 \times 10^4 \text{ V/cm} \rightarrow \text{now large from } E_{max}$$

